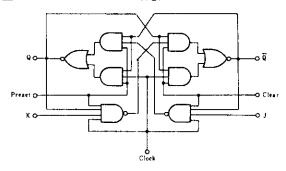
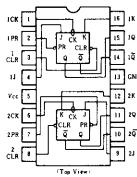
■BLOCK DIAGRAM(½)



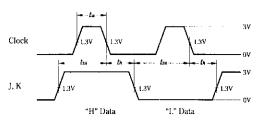
PIN ARRANGEMENT



■RECOMMENDED OPERATING CONDITIONS

Item Clock frequency		Symbol	min	typ	max	Unit
		felock	0	-	30	MHz
	Clock High		20	_	_	ns
Pulse width	Clear Preset Low	tw	25	_	-	
Setup time	"H"Data		20↓		_	
	"L"Data	for .	20↓	_	_	ns
Hold time		th	01	-	-	ns

ETIMING DEFINITION



Note) 1; The arrow indicates the falling edge.

ELECTRICAL CHARACTERISTICS ($Ta = -20 \sim +75^{\circ}$ C)

Item		Symbol	Test Conditions	min	typ*	max	Unit	
Input voltage		VIH			2.0	_	_	v
		VIL			-		0.8	v
Output voltage		Voн	$V_{CC} = 4.75 \text{V}, V_{IH} = 2 \text{V}, V_{IL} = 0.8 \text{V}, I_{OH} = -400 \mu \text{A}$		2.7	_	_	V
			$V_{CC} = 4.75 \text{V}, V_{IH} = 2 \text{V}, V_{IL} = 0.8 \text{V}$	Io1 = 8mA	_		0.5	v
		Vol		IoL = 4mA	-	_	0.4	
	J, K		———		-		20	μА
	Clear	1 _			_	60		
	Preset	Іін	$V_{CC} = 5.25 \text{V}, V_{I} = 2.7 \text{V}$			_	60	
	Clock				_	_	80	
	J, K		We have a state of the state of		-	_	-0.4	mA.
•	Clear					-0.8		
Input current	Preset	lit**	$V_{CC} = 5.25 \text{V}, V_I = 0.4 \text{V}$			_	-0.8	
	Clock			_	_	-0.8		
	J, K				_		0.1	m A
	Clear	1 _			_		0.3	
	Preset	I,	$V_{CC}=5.25V, V_I=7V$	$V_I = 7 \text{ V}$			0.3	
	Clock	1					0.4	
Short-circuit output current		los	$V_{CC} = 5.25 \text{V}$		- 20	_	-100	mA
Supply current ***			$V_{CC} = 5.25 \text{V}$			4	6	m.A
Input clamp voltage	e	Vik	$V_{CC} = 4.75 \text{V}, I_{IN} = -18 \text{mA}$		— —		-1.5	v

^{*} VCC = 5V, Ta = 25°C

^{**} IIL should not be measured when preset and clear inputs are low at same time.

^{***} With all outputs open, ICC is measured with the Q and Q outputs high in turn.

At the time of measurement, the clock input is grounded.

EFUNCTION TABLE

	,	Outputs				
Preset	Clear	Clock	J	К	Q	Q
L	Н	×	×	×	Н	L
Н	L	×	×	×	L	Н
L	L	×	×	×	н•	н.
Н	Н	i	L	L	Qσ	Qπ
Н	Н	ļ	Н	L	Н	L
Н	Н	1	L	Н	L	Н
Н	Н	Ţ	Н	Н	Toggle	
Н	Н	Н	×	×	Qο	$\overline{\mathbf{Q}}_0$

Notes) H; high level, L; low level, X; irrelevant

1; transition from high to low level

 \mathbf{Q}_{o} , level of Q before the indicated steady-state input conditions were established.

Q₀; complement of Q₀ or level of Q before the indicated steady-state input conditions were established.

Toggle; each output changes to the complement of its previous level on each active transition indicated by 4.

*; This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

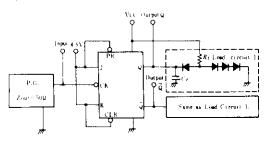
ESWITCHING CHARACTERISTICS ($V_{CC} = 5V$, $T_a = 25^{\circ}C$)

Item	Symbol	Inputs	Outputs	Test Conditions	min	typ	max	Unit
Maximum clock frequency	fmax				30	45		MHz
Propagation delay time	tpl.n	Clear	Q, Q	$C_L = 15 \text{pF}, R_L = 2 \text{k}\Omega$		15	20	ns
	tphi.	Preset Clock				15	20	ns

ETESTING METHOD

1) Test Circuit

1.1) fmex. tPLH. tPHL (Clock →Q,Q)

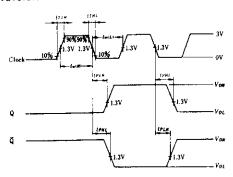


Notes) 1. Test is put into the each flip-flop

2. All diodes are 1S2074 (H)

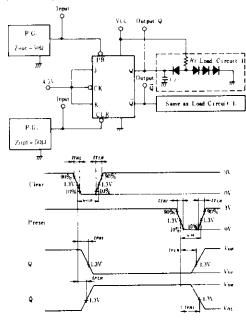
3. CL includes probe and jig capacitance.

Waveform



Note) Clock input pulse; $t_{TLH} \le 15$ ns, $t_{THL} \le 6$ ns, PRR = 1MHz, duty cycle=50% and: for f_{max} , $t_{TLH} = t_{THL} \le 2.5$ ns.

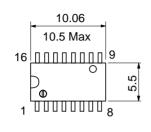
1.2) tPHL, tPLH (Clear, Preset→Q,Q)

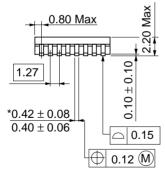


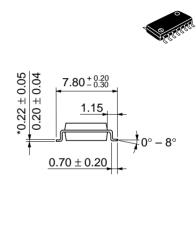
Note) Clear and preset input pulse; $t_{TLH} \le 15 \text{ns}, t_{THL} \le 6 \text{ns}, PRR = 1 \text{MHz}$

Unit: mm 19.20 20.00 Max 16 7.40 Max 6.30 1.3 1.11 Max 7.62 5.06 Max 2.54 Min 0.51 Min $0.25^{+0.13}_{-0.05}$ 0.48 ± 0.10 2.54 ± 0.25 $0^{\circ} - 15^{\circ}$ Hitachi Code DP-16 **JEDEC** Conforms EIAJ Conforms Weight (reference value) 1.07 g

Unit: mm



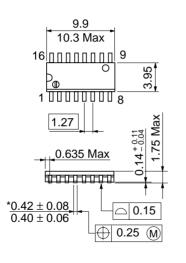


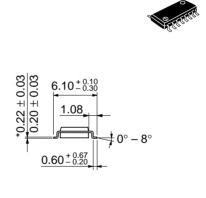


*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DA
JEDEC	_
EIAJ	Conforms
Weight (reference value)	0.24 g

Unit: mm





*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

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